

Institute of High Energy Physics Chinese Academy of Sciences



DRD3

Low Gain Avalanche Detectors with deep Carbon implantation

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WG3/WP3 - Extreme fluence and radiation damage characterization



- Low gain avalanche detectors with 30ps temporal resolution designed by IHEP are chosen as a part of HGTD for HL-LHC. These detectors (denoted as W0) are:
 - Carbonated.
 - Different implantation depth for gain layer and Carbon.
 - High thermal load for Carbon.
- Growing need for enhanced radiation hardness in detectors:
 - to meet higher requirements, we have investigated devices utilizing a deep carbon implantation layer.

Parameter	Unit	LHC	HL-LHC	HE-LHC	FCC-hh
Total number of pp collisions	1010	2.6	26	91	324
Charged part. flux at 2.5 cm, est.(FLUKA)	${ m GHzcm^{-2}}$	0.1	0.7	2.7	8.4 (10)
1 MeV-neq fluence at 2.5 cm, est.(FLUKA)	$10^{16}{ m cm}^{-2}$	0.4	3.9	16.8	84.3 (60)
Total ionising dose at 2.5 cm, est.(FLUKA)	MGy	1.3	13	54	270 (300)
$dE/d\eta _{\eta=5}$ [331]	GeV	316	316	427	765
$dP/d\eta _{\eta=5}$	kW	0.04	0.2	1.0	4.0
90% b $\overline{\mathrm{b}} p_T^{\mathrm{b}} > 30\mathrm{GeV/c}$ [332]	$ \eta $ <	3	3	3.3	4.5
VBF jet peak [332]	$ \eta $	3.4	3.4	3.7	4.4
90% VBF jets [332]	$ \eta <$	4.5	4.5	5.0	6.0
$90\% \text{ H} \rightarrow 4l \text{ [332]}$	$ \eta $ <	3.8	3.8	4.1	4.8

Table 7.1: Key numbers relating the detector challenges at the different accelerators.



Roadmap of IHEP sensors

		IHEP_IMEv3 LGAD deigns				
IHEP_IMEv1	Sensor		Diffuse	C dose(a.u.)		
2020	W15		CHBL	0.5	Different B dose	
IHEP_IMEv2 2021-2022 W16 W17 IHEP_IMEv3 2022-		W16Q1		0.2		
		W16Q2		0.3		
		W16Q3		0.4		
	W16	W16Q4	CHBL	0.5	Interpolate v2w7 to minimize the C factor.	
	W17	W17Q1		0.6		
		W17Q2		0.7		
		W17Q3		0.8		
		W17Q4		0.9		
W18		V18	CMBL	0.5, 0.8, 1, 2	Change c thermal load	
W20 w21 w22		CHBL	0.2			
		CHBL	0.5	Different C		
			CHBL	1	Борит	



Doping profiles and Vgl





- Carbon and Boron are implanted with very closs depth.
- 3 deep carbonated wafers differ only in carbom dose.
- Gain layer deactivated with increasing carbon-density, up to 6%.

Bias Voltage [V]



Radiation resistance 1

• 80MeV proton irradiation at China Spallation Neutron Source (csns) up to $2.5e15 n_{eq}/cm^2$.





Radiation resistance 2

- Modeling c factors
 - 1.Assume carbon with profile1 protects boron.
 - 2.Only carbon with profile 2 affects.





Wafer	W20	W21	W22	WO	
C (1e-16cm2) proton	2.48	1.63	1.44	3.11	
C (1e-16cm2) netron	-	-	-	1.06	
C (neutron) Assumption 1	1.18	0.74	0.50	-	
C (neutron) Assumption 2		0.82	0.70		
Ratio (proton / neutron)	2.10	2.20	2.88	2.02	
		1.99	2.06	2.93	

- Ratio of proton c-factor and neutron c-factor derived from modeling: between 2 and 3.
- Improvement in radiation hardness compared with shallow carbonated LGAD (W0).



Radiation resistance 3

- Charge collection and time resolution:
 - A comparison with pre-W4, both much improvement especially at lower irradiation dose.
 - W22 shows slightly smaller c value, it's charge collection is not better than W21.





Summary

- LGAD devices with Boron and Carbon implanted with same depth is designed by IHEP.
 - Common features:
 - All wafers utilize the same gain layer design.
 - The carbon annealing process involves a high thermal load to create a wide active profile.
 - Among all recipes with different Carbon energy and dose, the deep-implanted design with moderate dose exhibits best performance.
 - Challenges:
 - The carbon profile is limited by anneal temperature.
 - Gain layer acceptors become deactivated as carbon density increases.
 - High leakage current are inevitable issue worsening with gain layer carbon density.





• CV curve















IMECAS About CSNS





Facility	Proton energy (MeV)	Proton flux (p \cdot cm ⁻² \cdot s ⁻¹)	Beam spot size (cm)
CSNS APEP	10 - 80	10 ⁷ — 10 ¹⁰	1×1-5×5

- Beam Energy: 80MeV
- > Beam Size: $20 \times 20mm^2$





INTEGAS Irradiation setup





Proton beam spot

